

## FDS4080N7 40V N-Channel FLMP PowerTrench<sup>®</sup> MOSFET

### **General Description**

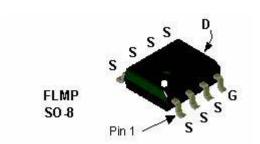
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for "low side" synchronous rectifier operation, providing an extremely low  $R_{DS(ON)}$  in a small package.

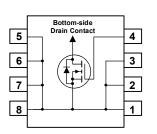
## Applications

- Synchronous rectifier
- DC/DC converter

## Features

- 13 A, 40 V  $R_{DS(ON)}$  = 10 m $\Omega$  @ V<sub>GS</sub> = 10 V
- High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$
- High power and current handling capability
- Fast switching (Qg = 30 nC)
- FLMP SO-8 package: Enhanced thermal performance in industry-standard package size





## Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage			40	V
V <sub>GSS</sub>	Gate-Source Voltage			± 20	V
I <sub>D</sub>	Drain Current – Continuous (Note 1a)			13	Α
	– Pulsed			60	
PD	Power Diss	ipation for Single Operation	(Note 1a)	3.9	W
	Operating and Storage Junction Temperature Range			–55 to +150	°C
R <sub>0JA</sub>	I Charac		ent (Note 1a)	38 1	°C/W
Therma R <sub>θJA</sub> R <sub>θJC</sub> Packag	I Charac Thermal Re Thermal Re e Markin	teristics sistance, Junction-to-Ambie sistance, Junction-to-Ambie g and Ordering In	ent (Note 1a) ent formation	38 1	°C/W
<b>Therma</b> R <sub>θJA</sub> R <sub>θJC</sub>	I Charac Thermal Re Thermal Re e Markin	teristics sistance, Junction-to-Ambie sistance, Junction-to-Ambie	ent (Note 1a)	38	°C/W

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**Electrical Characteristics**  $T_{A} = 25^{\circ}C$  unless otherwise noted Min Symbol Max Units **Parameter Test Conditions** Тур Drain-Source Avalanche Ratings (Note 2) Drain-Source Avalanche Energy Single Pulse, V<sub>DD</sub> = 10V, I<sub>D</sub>=13A 200  $\mathsf{E}_{\mathsf{AS}}$ mJ Drain-Source Avalanche Current 13 А  $I_{AS}$ **Off Characteristics** Drain–Source Breakdown Voltage  $V_{GS} = 0 V, I_D = 250 \mu A$ 40 V  $\mathsf{BV}_{\mathsf{DSS}}$ Breakdown Voltage Temperature  $\Delta BV_{DSS}$  $I_D$  = 250  $\mu$ A, Referenced to 25°C 44 mV/°C Coefficient  $\Delta T_{\rm J}$ V<sub>DS</sub> = 32 V, V<sub>GS</sub> = 0 V Zero Gate Voltage Drain Current 1 IDSS μA V<sub>GS</sub> = 20 V, V<sub>DS</sub> = 0 V Gate-Body Leakage, Forward 100 nA I<sub>GSSF</sub> Gate-Body Leakage, Reverse  $V_{GS} = -20 \text{ V}$ ,  $V_{DS} = 0 \text{ V}$ -100 nA  $I_{GSSR}$ On Characteristics (Note 2) V Gate Threshold Voltage  $V_{DS} = V_{GS}, I_D = 250 \ \mu A$ 2 3.9 5  $V_{\text{GS(th)}}$ Gate Threshold Voltage  $I_D = 250 \ \mu A$ , Referenced to  $25^{\circ}C$  $\Delta V_{GS(th)}$ mV/°C -8 Temperature Coefficient  $\Delta T_{\rm J}$  $V_{GS}$  = 10 V,  $I_{D}$  = 13 A R<sub>DS(on)</sub> Static Drain-Source 7.8 10 mΩ **On-Resistance**  $V_{GS}$  = 10 V,  $I_D$  = 13 A,  $T_J$ =125°C 12 21 Forward Transconductance  $V_{DS} = 5 V$ ,  $I_D = 13 A$ 41 S **g**fs **Dynamic Characteristics** pF Input Capacitance 1750  $C_{\text{iss}}$ V<sub>DS</sub> = 20 V, V<sub>GS</sub> = 0 V,  $C_{oss}$ **Output Capacitance** f = 1.0 MHz 357 pF  $C_{\text{rss}}$ **Reverse Transfer Capacitance** 138 pF Switching Characteristics (Note 2)  $V_{DD} = 20 V$ ,  $I_D = 1 A$ , Turn-On Delay Time 12 21 ns t<sub>d(on)</sub>  $V_{GS}$  = 10 V,  $R_{GEN}$  = 6  $\Omega$ Turn-On Rise Time 8 17 tr ns 29 Turn-Off Delay Time 46 t<sub>d(off)</sub> ns Turn–Off Fall Time 14 25 tf ns  $V_{DS}$  = 20 V,  $I_{D}$  = 13 A,  $Q_g$ **Total Gate Charge** 30 40 nC  $V_{GS} = 10 V$  $\mathsf{Q}_{\mathsf{gs}}$ Gate-Source Charge 9 nC  $Q_{gd}$ Gate-Drain Charge 10 nC **Drain–Source Diode Characteristics and Maximum Ratings** Maximum Continuous Drain-Source Diode Forward Current 3.2 А Is Drain-Source Diode Forward  $V_{\text{SD}}$  $V_{GS} = 0 V$ , I<sub>S</sub> = 3.2 A (Note 2) 0.7 1.2 V Voltage

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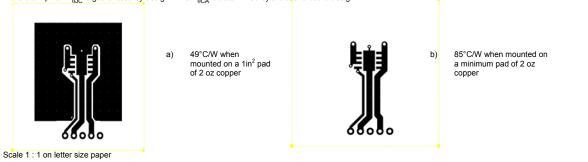
## **Electrical Characteristics**

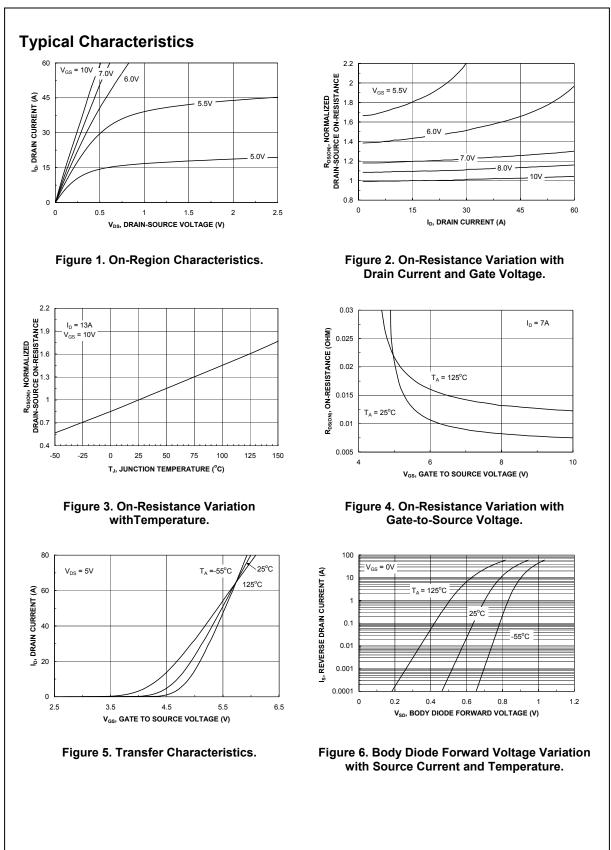
2. Pulse Test: Pulse Width <  $300\mu$ s, Duty Cycle < 2.0%

 $T_A = 25^{\circ}C$  unless otherwise noted

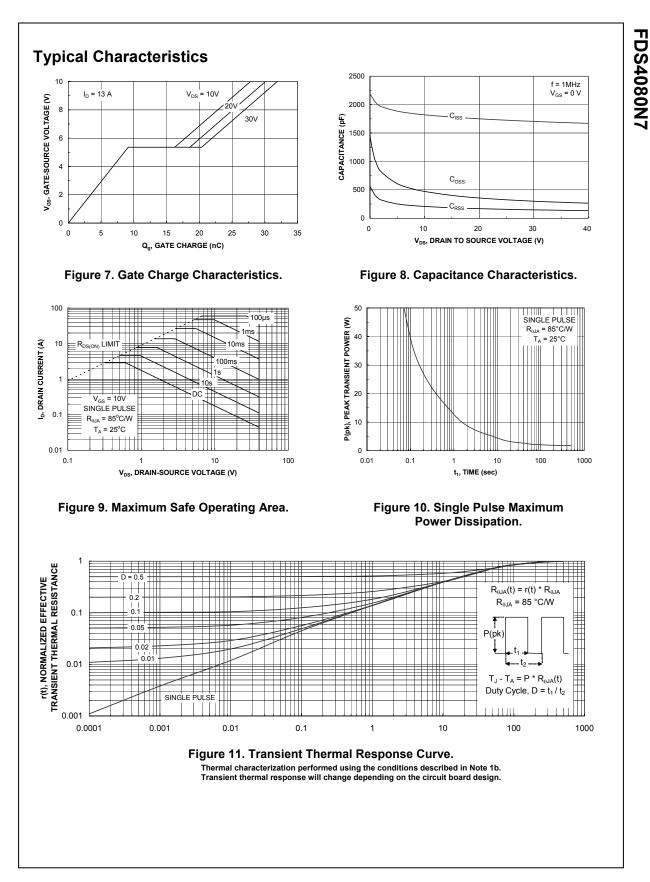
#### Notes:

1. R<sub>0JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.

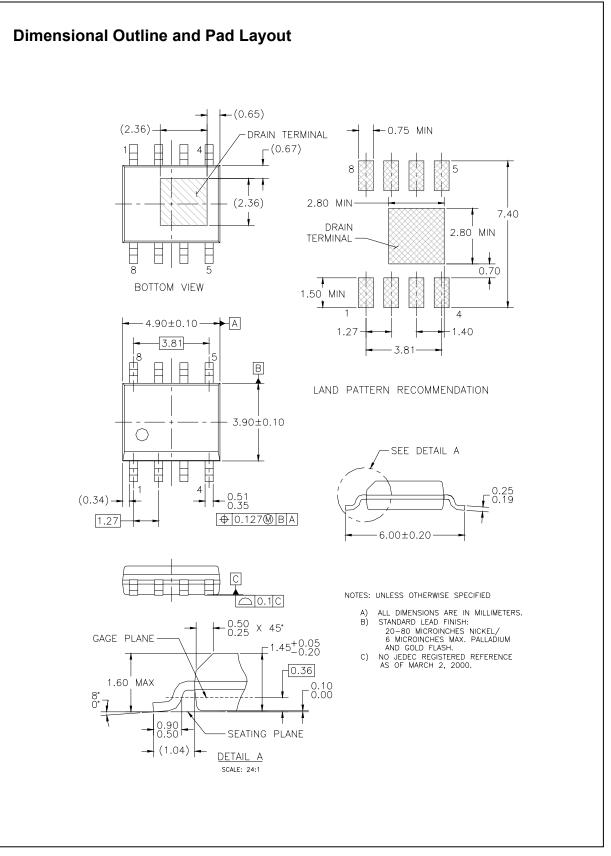




FDS4080N7 Rev D1 (W)



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